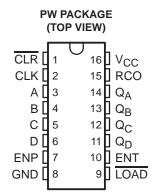
- Qualified for Automotive Applications
- Wide Operating Voltage Range of 2 V to 6 V
- Outputs Can Drive Up To 10 LSTTL Loads
- Low Power Consumption, 80-μA Max I_{CC}
- Typical t_{pd} = 14 ns
- ±4-mA Output Drive at 5 V
- Low Input Current of 1 μA Max
- Internal Look-Ahead for Fast Counting

description/ordering information

This synchronous, presettable counter features an internal carry look-ahead for application in high-speed counting designs. The SN74HC163 is a 4-bit binary counter. Synchronous operation is provided by having all flip-flops clocked

- Carry Output for n-Bit Cascading
- Synchronous Counting
- Synchronously Programmable



simultaneously so that the outputs change coincident with each other when instructed by the count-enable (ENP, ENT) inputs and internal gating. This mode of operation eliminates the output counting spikes normally associated with synchronous (ripple-clock) counters. A buffered clock (CLK) input triggers the four flip-flops on the rising (positive-going) edge of the clock waveform.

This counter is fully programmable; that is, it can be preset to any number between 0 and 9 or 15. As presetting is synchronous, setting up a low level at the load input disables the counter and causes the outputs to agree with the setup data after the next clock pulse, regardless of the levels of the enable inputs.

The clear function for the SN74HC163 is synchronous. A low level at the clear (\overline{CLR}) input sets all four of the flip-flop outputs low after the next low-to-high transition of CLK, regardless of the levels of the enable inputs. This synchronous clear allows the count length to be modified easily by decoding the Q outputs for the maximum count desired. The active-low output of the gate used for decoding is connected to \overline{CLR} to synchronously clear the counter to 0000 (LLLL).

The carry look-ahead circuitry provides for cascading counters for n-bit synchronous applications without additional gating. ENP, ENT, and a ripple-carry output (RCO) are instrumental in accomplishing this function. Both ENP and ENT must be high to count, and ENT is fed forward to enable RCO. Enabling RCO produces a high-level pulse while the count is maximum (9 or 15 with Q_A high). This high-level overflow ripple-carry pulse can be used to enable successive cascaded stages. Transitions at ENP or ENT are allowed, regardless of the level of CLK.

ORDERING INFORMATION†

TA	PACKAGE‡		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	TSSOP – PW Tape and ree		SN74HC163IPWRQ1	HC163I

[†] For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

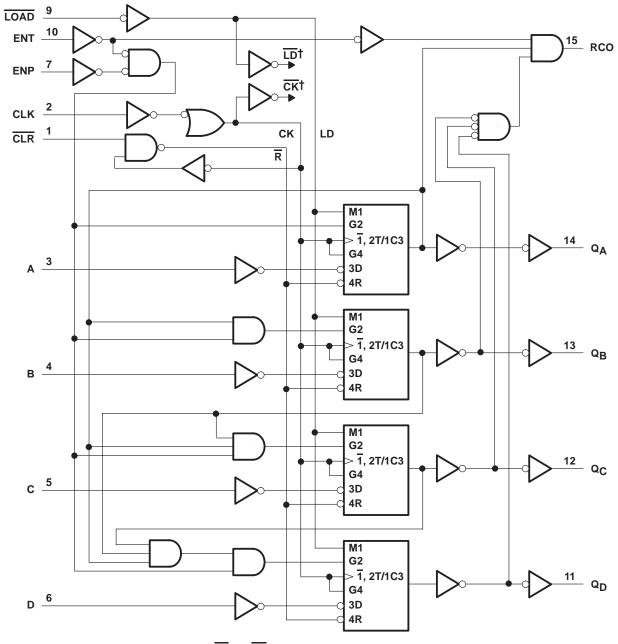


[‡] Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.

description/ordering information (continued)

This counter features a fully independent clock circuit. Changes at control inputs (ENP, ENT, or $\overline{\text{LOAD}}$) that modify the operating mode have no effect on the contents of the counter until clocking occurs. The function of the counter (whether enabled, disabled, loading, or counting) is dictated solely by the conditions meeting the stable setup and hold times.

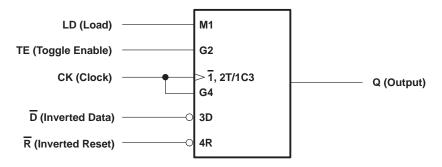
logic diagram (positive logic)



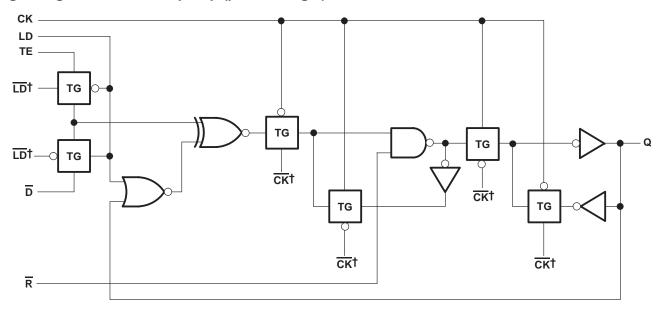
[†] For simplicity, routing of complementary signals $\overline{\mathsf{LD}}$ and $\overline{\mathsf{CK}}$ is not shown on this overall logic diagram. The uses of these signals are shown on the logic diagram of the D/T flip-flops.



logic symbol, each D/T flip-flop



logic diagram, each D/T flip-flop (positive logic)

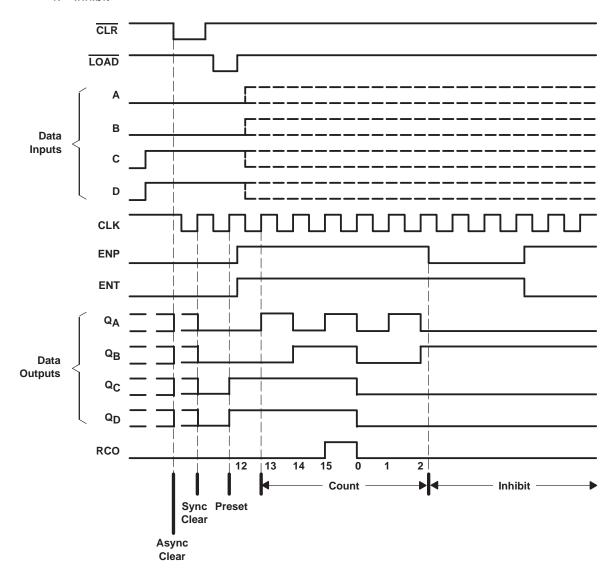


 $[\]dagger$ The origins of $\overline{\text{LD}}$ and $\overline{\text{CK}}$ are shown in the logic diagram of the overall device.

typical clear, preset, count, and inhibit sequence

The following sequence is illustrated below:

- 1. Clear outputs to zero (synchronous)
- 2. Preset to binary 12
- 3. Count to 13, 14, 15, 0, 1, and 2
- 4. Inhibit





SN74HC163-Q1 4-BIT SYNCHRONOUS BINARY COUNTER

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	\dots $-0.5\ V$ to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±25 mA
Continuous current through V _{CC} or GND	±50 mA
Package thermal impedance, θ _{JA} (see Note 2): PW package	108°C/W
Storage temperature range, T _{stq}	. −65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	V
		V _{CC} = 2 V	1.5			
VIH	High-level input voltage	V _{CC} = 4.5 V	3.15			V
		VCC = 6 V	4.2			
		V _{CC} = 2 V			0.5	
VIL	Low-level input voltage	V _{CC} = 4.5 V			1.35	V
		V _{CC} = 6 V			1.8	
٧ _I	Input voltage		0		VCC	V
Vo	Output voltage		0		VCC	V
		V _{CC} = 2 V			1000	
Δt/Δv‡	Input transition rise/fall time	V _{CC} = 4.5 V			500	ns
		VCC = 6 V			400	
TA	Operating free-air temperature		-40		85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51-7.

[‡] If this device is used in the threshold region (from V_{IL}max = 0.5 V to V_{IH}min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t_t = 1000 ns and V_{CC} = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST SOUDITIO	NO.	.,	Т	A = 25°C	;		B4 4 3/	
PARAMETER	TEST CONDITIO	NS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		
∨он	VI = VIH or VIL		6 V	5.9	5.999		5.9		V
	1	$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.34		
			2 V		0.002	0.1		0.1	
		$I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1	
VOL	VI = VIH or VIL		6 V		0.001	0.1		0.1	V
		I _{OL} = 4 mA	4.5 V		0.17	0.26		0.33	
		I _{OL} = 5.2 mA	6 V		0.15	0.26		0.33	
lį	VI = VCC or 0		6 V		±0.1	±100	Ξ	±1000	nA
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8	·	80	μΑ
Ci			2 V to 6 V		3	10		10	pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

				T _A = 1	25°C	84181	MAY	
			vcc	MIN	MAX	MIN	MAX	UNIT
			2 V		6		5	
fclock	Clock frequency		4.5 V		31		25	MHz
			6 V		36		29	
			2 V	80		100		
$t_{\mathbf{W}}$	Pulse duration	CLK high or low	4.5 V	16		20		ns
				14		17		
			2 V	150		190		
		A, B, C, or D	4.5 V	30		38		
			6 V	26		32		
			2 V	135		170		
		LOAD low	4.5 V	27		34		
			6 V	23		29		
			2 V	170		215		ns
t _{su}	Setup time before CLK↑	ENP, ENT	4.5 V	34		43		
			6 V	29		37		
			2 V	160		200		
		CLR low	4.5 V	32		40		
			6 V	27		34		
			2 V	160		200		
		CLR inactive	4.5 V	32		40		
			6 V	27		34		
			2 V	0		0		
th	Hold time, all synchronous inputs after CLK↑	4.5 V	0		0		ns	
			6 V	0		0		



SN74HC163-Q1 4-BIT SYNCHRONOUS BINARY COUNTER

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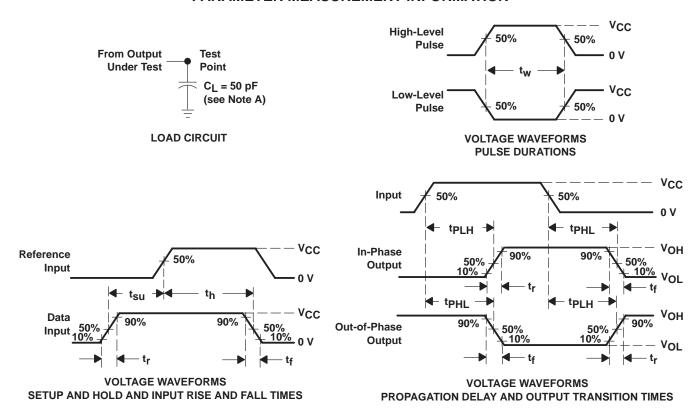
switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

242445752	FROM	то	.,	T,	ղ = 25°C	;			
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V	6	14		5		
fmax			4.5 V	31	40		25		MHz
			6 V	36	44		29		
			2 V		83	215		270	
	CLK	RCO	4.5 V		24	43		54	ns
			6 V		20	37		46	
			2 V		80	205		255	
^t pd		Any Q	4.5 V		25	41		51	
			6 V		21	35		43	
			2 V		62	195		245	
	ENT	RCO	4.5 V		17	39		49]
			6 V		14	33		42	
			2 V		38	75		95	
t _t		Any	4.5 V		8	15		19	ns
			6 V		6	13		16	

operating characteristics, $T_A = 25^{\circ}C$

		PARAMETER	TEST CONDITIONS	TYP	UNIT
Г	C _{pd}	Power dissipation capacitance	No load	60	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 6 \ ns$, $t_f = 6 \ ns$.
- C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



APPLICATION INFORMATION

n-bit synchronous counters

This application demonstrates how the look-ahead carry circuit can be used to implement a high-speed n-bit counter. The SN74HC163 counts in binary. Virtually any count mode (modulo-N, N₁-to-N₂, N₁-to-maximum) can be used with this fast look-ahead circuit.

The application circuit shown in Figure 2 is not valid for clock frequencies above 18 MHz (at 25° C and 4.5-V V_{CC}). The reason for this is that there is a glitch that is produced on the second stage's RCO and every succeeding stage's RCO. This glitch is common to all HC vendors that Texas Instruments has evaluated, in addition to the bipolar equivalents (LS, ALS, AS).

APPLICATION INFORMATION CLR Clear (L) _ LOAD M1 **RCO** Count (H)/ 3CT=MAX **ENT** G3 Disable (L) **ENP** G4 CLK > C5/2,3,4+ Load (L) 1,5D [1] Q_{A} [2] Q_{B} Count (H)/ Disable (L) [3] Q_{C} Q_D [4] Clock CTR CLR CT=0 LOAD **RCO** M1 3CT=MAX **ENT** G3 **ENP** G4 CLK > C5/2,3,4+ 1,5D [1] Q_A [2] Q_{B} [3] Q_{C} [4] Q_{D} **CTR** CLR CT=0 LOAD **RCO** M1 3CT=MAX **ENT** G3 **ENP** G4 CLK > C5/2,3,4+ 1,5D [1] Q_A [2] Q_B Q_{C} [3] [4] Q_D CT=0 CLR LOAD M1 **RCO** 3CT=MAX **ENT** G3 **ENP** G4 **CLK** > C5/2,3,4+ 1,5D [1] Q_{A} [2] Q_{B} Q_{C} [3] [4] Q_D

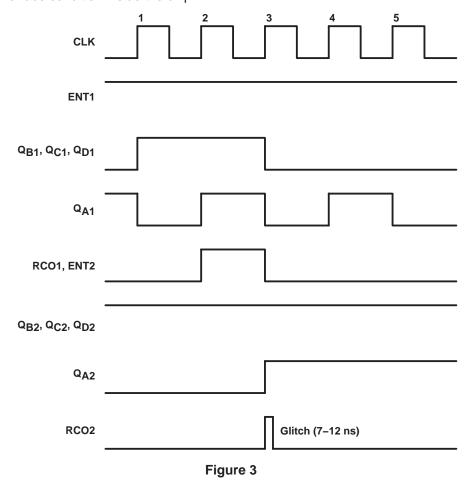
To More-Significant Stages
Figure 2



APPLICATION INFORMATION

n-bit synchronous counters (continued)

The glitch on RCO is caused because the propagation delay of the rising edge of Q_A of the second stage is shorter than the propagation delay of the falling edge of ENT. RCO is the product of ENT, Q_A , Q_B , Q_C , and Q_D (ENT \times $Q_A \times Q_B \times Q_C \times Q_D$). The resulting glitch is about 7 ns to 12 ns in duration. Figure 3 shows the condition in which the glitch occurs. For simplicity, only two stages are being considered, but the results can be applied to other stages. Q_B , Q_C , and Q_D of the first and second stage are at logic one, and Q_A of both stages are at logic zero (1110 1110) after the first clock pulse. On the rising edge of the second clock pulse, Q_A and RCO of the first stage go high. On the rising edge of the third clock pulse, Q_A and RCO of the first stage return to a low level, and Q_A of the second stage goes to a high level. At this time, the glitch on RCO of the second stage appears because of the race condition inside the chip.



The glitch causes a problem in the next stage (stage three) if the glitch is still present when the next rising clock edge appears (clock pulse 4). To ensure that this does not happen, the clock frequency must be less than the inverse of the sum of the clock-to-RCO propagation delay and the glitch duration (t_g). In other words, $t_{max} = 1/(t_{pd} \text{ CLK-to-RCO} + t_g)$. For example, at 25°C at 4.5-V t_{CC} , the clock-to-RCO propagation delay is 43 ns and the maximum duration of the glitch is 12 ns. Therefore, the maximum clock frequency that the cascaded counters can use is 18 MHz. The following tables contain the t_{clock} , t_{tw} , and t_{tw} specifications for applications that use more than two 'HC163 devices cascaded together.

APPLICATION INFORMATION

n-bit synchronous counters (continued)

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		.,	T _A = 2	25°C	BAIN!	MAY	
		vcc	MIN	MAX	MIN	MAX	UNIT
		2 V		3.6		2.9	
fclock	Clock frequency	4.5 V		18		14	MHz
		6 V		21		17	
		2 V	140		170		
t _W	Pulse duration, CLK high or low	4.5 V	28		36		ns
		6 V	24		30	·	

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Note 4)

DADAMETED	FROM	то	.,	T _A = 25°C		NAIN!	MAV	
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	MAX	MIN	MAX	UNIT
			2 V	3.6		2.9		
fmax			4.5 V	18		14		MHz
			6 V	21		17		

NOTE 4: These limits apply only to applications that use more than two 'HC163 devices cascaded together.

If the SN74HC163 device is used as a single unit, or only two are cascaded together, then the maximum clock frequency that the device can use is not limited because of the glitch. In these situations, the device can be operated at the maximum specifications.

A glitch can appear on the RCO of a single SN74HC163 device, depending on the relationship of ENT to CLK. Any application that uses RCO to drive any input, except an ENT of another cascaded SN74HC163 device, must take this into consideration.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
SN74HC163IPWRG4Q1	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC163I
SN74HC163IPWRG4Q1.A	Active	Production	TSSOP (PW) 16	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC163I

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF SN74HC163-Q1:

Catalog: SN74HC163

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 11-Nov-2025

• Military : SN54HC163

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 24-Jul-2025

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	U	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC163IPWRG4Q1	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 24-Jul-2025



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC163IPWRG4Q1	TSSOP	PW	16	2000	353.0	353.0	32.0



SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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